

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/628,228	<b>Applicant(s)/Patent under Reexamination</b> TAKENAKA, HIDEKI
	<b>Examiner</b> Alex Liew	<b>Art Unit</b> 2624

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
382/118 (limited to text search)	10/5/2006	AL
382/118 limited to text search	2/7/2007	AL
382/115,116,118 limited to text search	7/19/2007	AL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner